

PERFORMANCE OF PLANAR PIXEL MODULES FOR THE PHASE-2 UPGRADE OF THE CMS INNER TRACKER

CMS Inner Tracker Upgrade for the High-Luminosity LHC

The Inner Tracker of the Compact Muon Solenoid (CMS) experiment will be entirely upgraded for the High-Luminosity Phase of the Large Hadron Collider (HL-LHC)^[1].

Highlights Luminosity: $7.5 \times 10^{34} \text{ cm}^{-2} \text{ s}^{-1}$ Integrated luminosity: $3000 - 4000 \text{ fb}^{-1}$ Pile-up: $\langle \mu \rangle = 200$ Φ_{max} planar modules = $1 \times 10^{16} \text{ n}_{\text{eq}} \text{ cm}^{-2}$

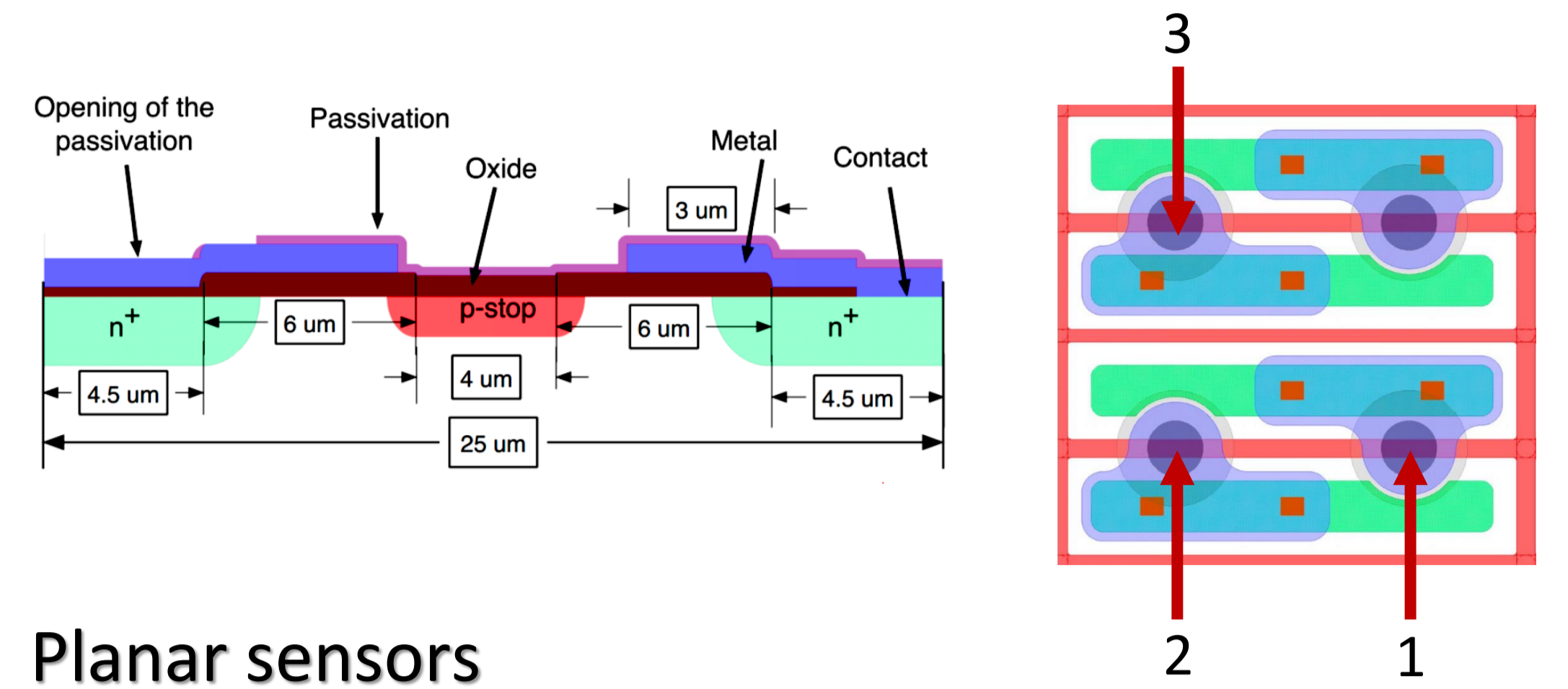
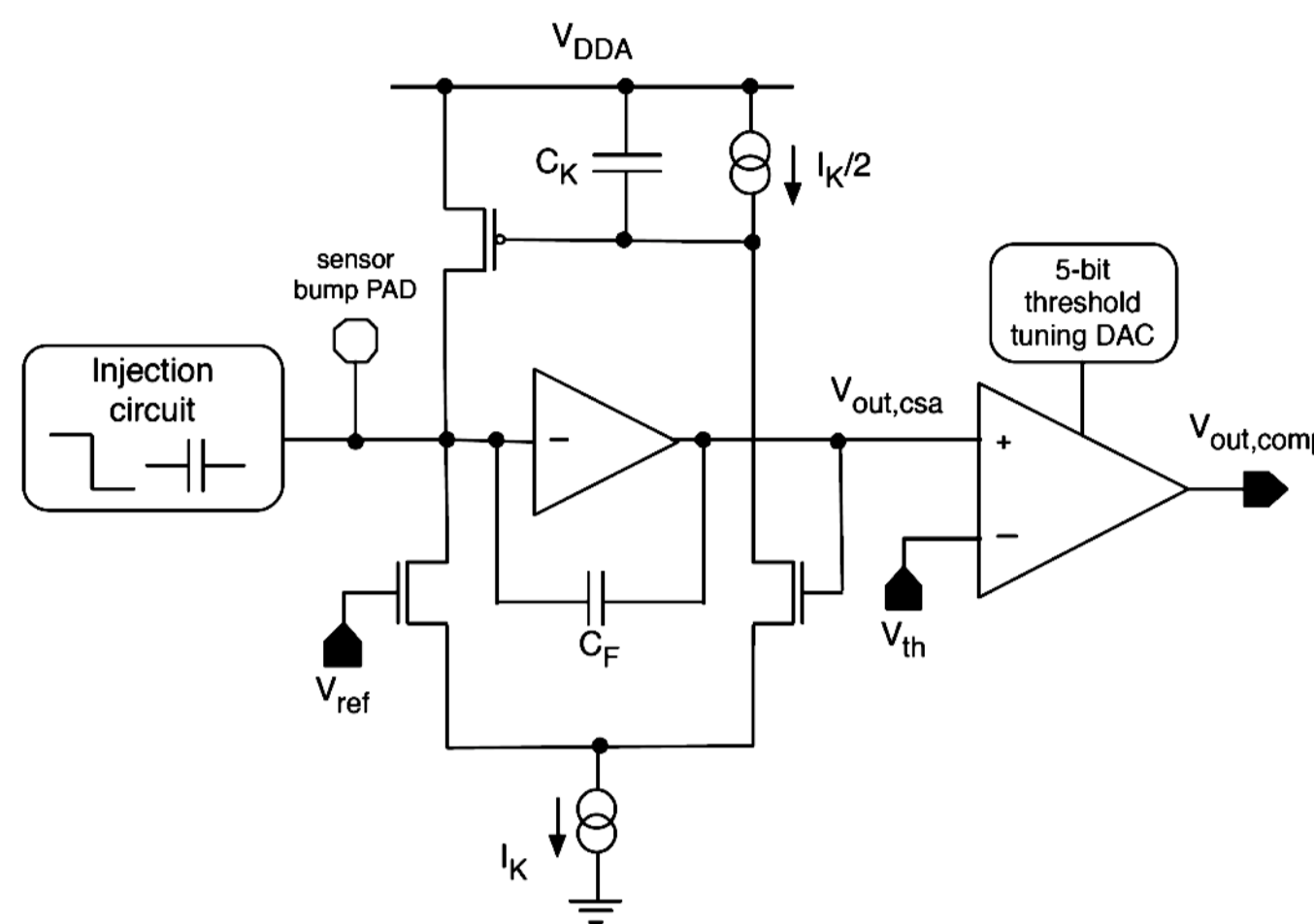
New pixel detectors for the CMS Inner Tracker

Pixel detectors of the Inner Tracker will feature a new **readout chip** (RD53C_CMS) and **sensor design**

RD53B_CMS readout chips^[2]

Implemented in **65 nm CMOS radiation-hard** technology:

- **432 x 336** pixels with $50 \times 50 \mu\text{m}^2$ pitch
- **Analog Front-End:**
 - **Single stage** with Krummenacher feedback
 - Low power **comparator**
 - 4 bit **counter** for charge digitization
 - 5 bit in-pixel DAC for **threshold tuning**



Planar sensors

- **n⁺-in-p** Hamamatsu Photonics (HPK)
- Pitches of $25 \times 100 \mu\text{m}^2$ and active thickness of **150 μm**
- **Bitten** design: cutout in the neighboring pixel

Threshold studies

Pixels tuned to a **common threshold** to zero-suppress noise hits:

- Hit detection changes as function of **time** within the bunch crossing
- Feature of the **readout's architecture**
- Impact on the measured **crosstalk (XT)**

Crosstalk studies

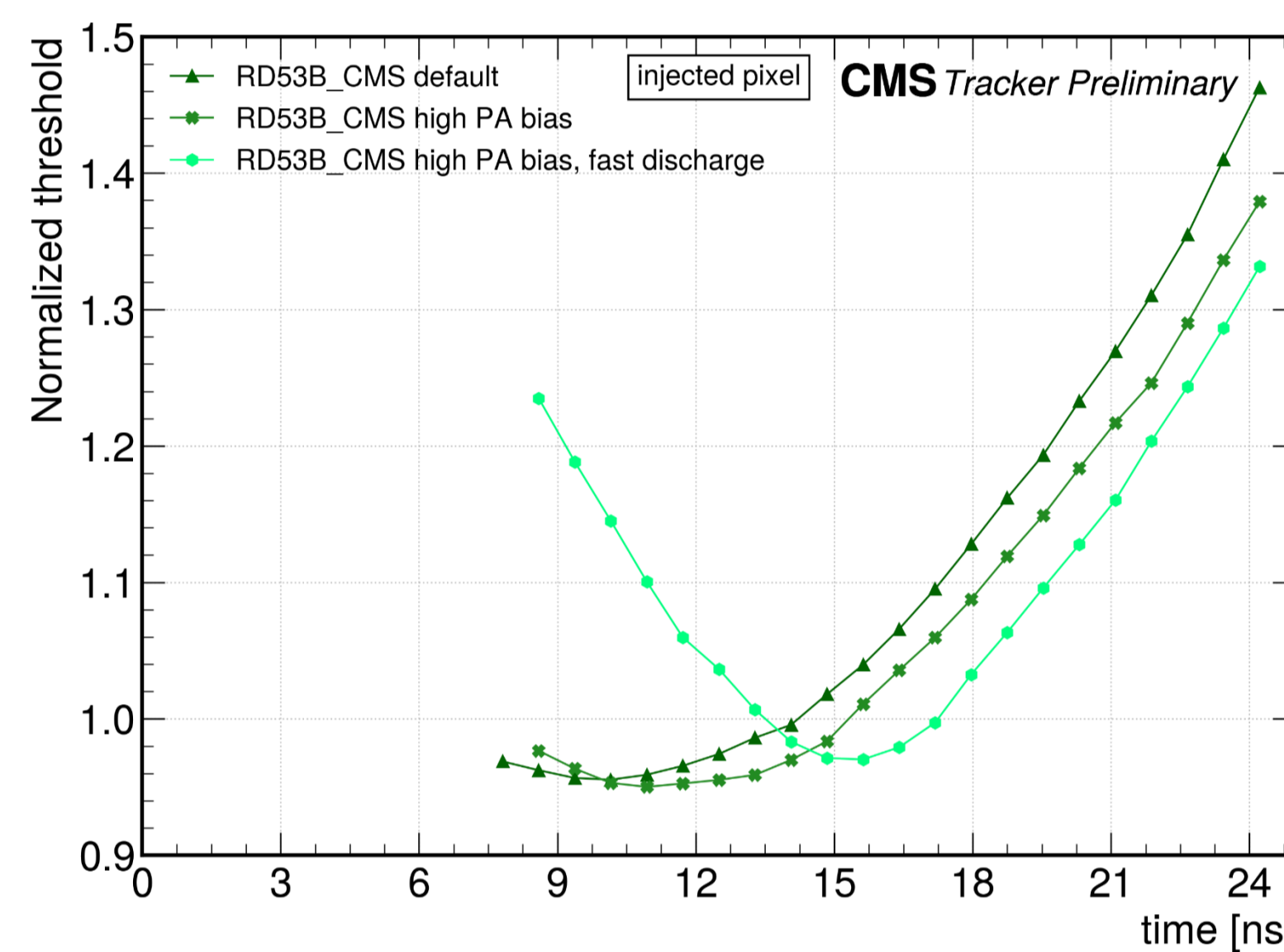
Must remain **<10%** for all geometrical configurations:

- **Coupled** pixels (1-2) with highest inter-pixel capacitance (14 fF)
- **Uncoupled** pixels (1-3) with second highest (6.5 fF)
- Avoid biasing of **reconstructed hit position**

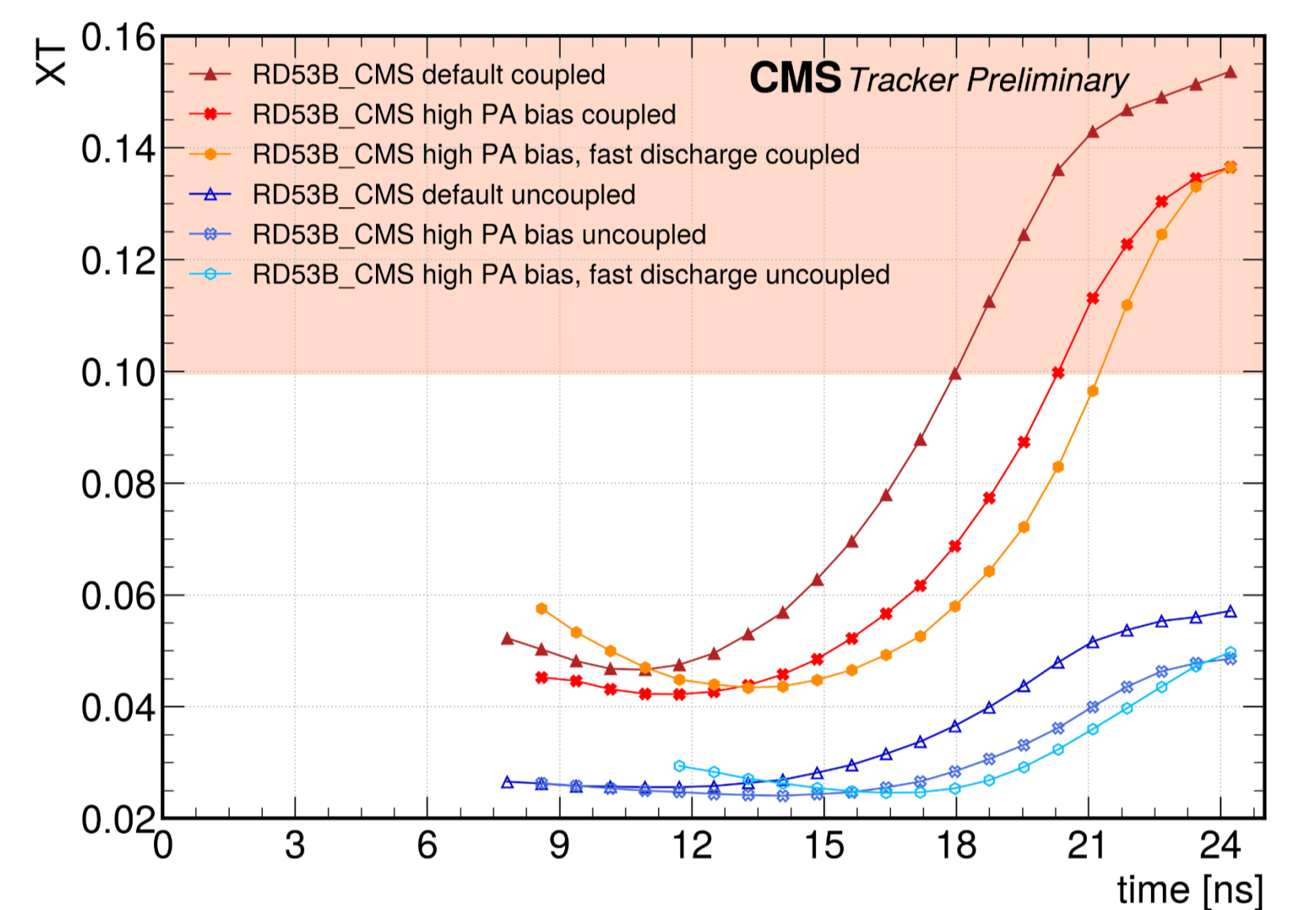
Phasing of clock in final experiment will target highest efficiency:

- Lowest threshold \rightarrow minimum of threshold near crosstalk minimum

Effective threshold



Crosstalk



XT \sim 5% close to the threshold's minimum

Test beam measurements

Samples measured at DESY II Test Beam facility with **5.2 GeV e⁻/e⁺ beam**.

Modules **irradiated with 24 GeV/c protons** at Proton Irradiation Facility:

- **Non-uniform** fluence across **columns**
- Ranges from $\Phi_{\text{eq}} = 0.5 \times 10^{16} \text{ cm}^{-2}$ to $\Phi_{\text{eq}} = 1.0 \times 10^{16} \text{ cm}^{-2}$

Individual sections with different average fluences have been studied.

Observables $\epsilon_{\text{hit}} = \frac{N_{\text{tracks}}^{\text{DUT}}}{N_{\text{tracks}}^{\text{total}}}$ $\alpha = 1 - \frac{N_{\text{pxl}}^{\text{masked}}}{N_{\text{pxl}}^{\text{total}}}$ $\sigma_{\text{hit}} = \sqrt{\sigma_{\text{res}}^2 - \sigma_{\text{tel}}^2}$

Main **module requirements:**

- Number of **masked pixels** **<1%** (noise occupancy threshold $< 10^{-4}$)
- **Average noise occupancy** of unmasked pixels **<10⁻⁶**
- At vertical incidence, for irradiated modules:

$$\Phi_{\text{ref}} = 5 \times 10^{15} \text{ n}_{\text{eq}} \text{ cm}^{-2} \begin{cases} \Phi_{\text{eq}} < \Phi_{\text{ref}} & \epsilon_{\text{hit}} \times \alpha > 99\% & V_{\text{bias}} \leq 600 \text{ V} \\ \Phi_{\text{eq}} > \Phi_{\text{ref}} & \epsilon_{\text{hit}} \times \alpha > 98\% & V_{\text{bias}} \leq 800 \text{ V} \end{cases}$$

Studies on $\Phi_{\text{eq}} = 1.0 \times 10^{16} \text{ cm}^{-2}$ for different **thresholds:**

- Meet requirement for $\epsilon_{\text{hit}} \times \alpha$
- Noisy pixels above requirement for threshold = 1000 e⁻

Threshold $\geq 1200 \text{ e}^-$ to fulfil $\epsilon_{\text{hit}} \times \alpha$ and noise requirements

σ_{hit} better than binary limit before irradiation:

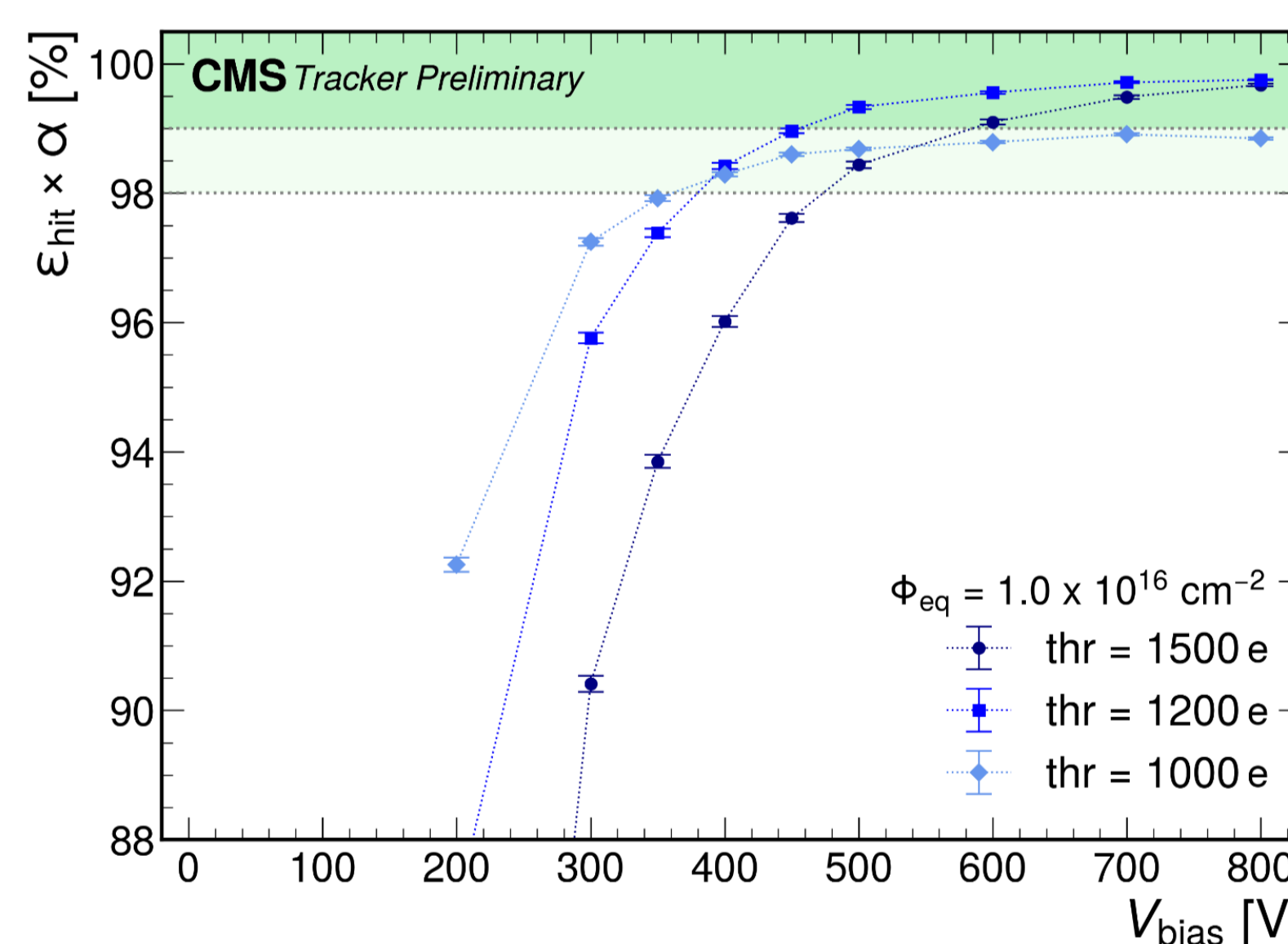
- Charge sharing

Aim after irradiation:

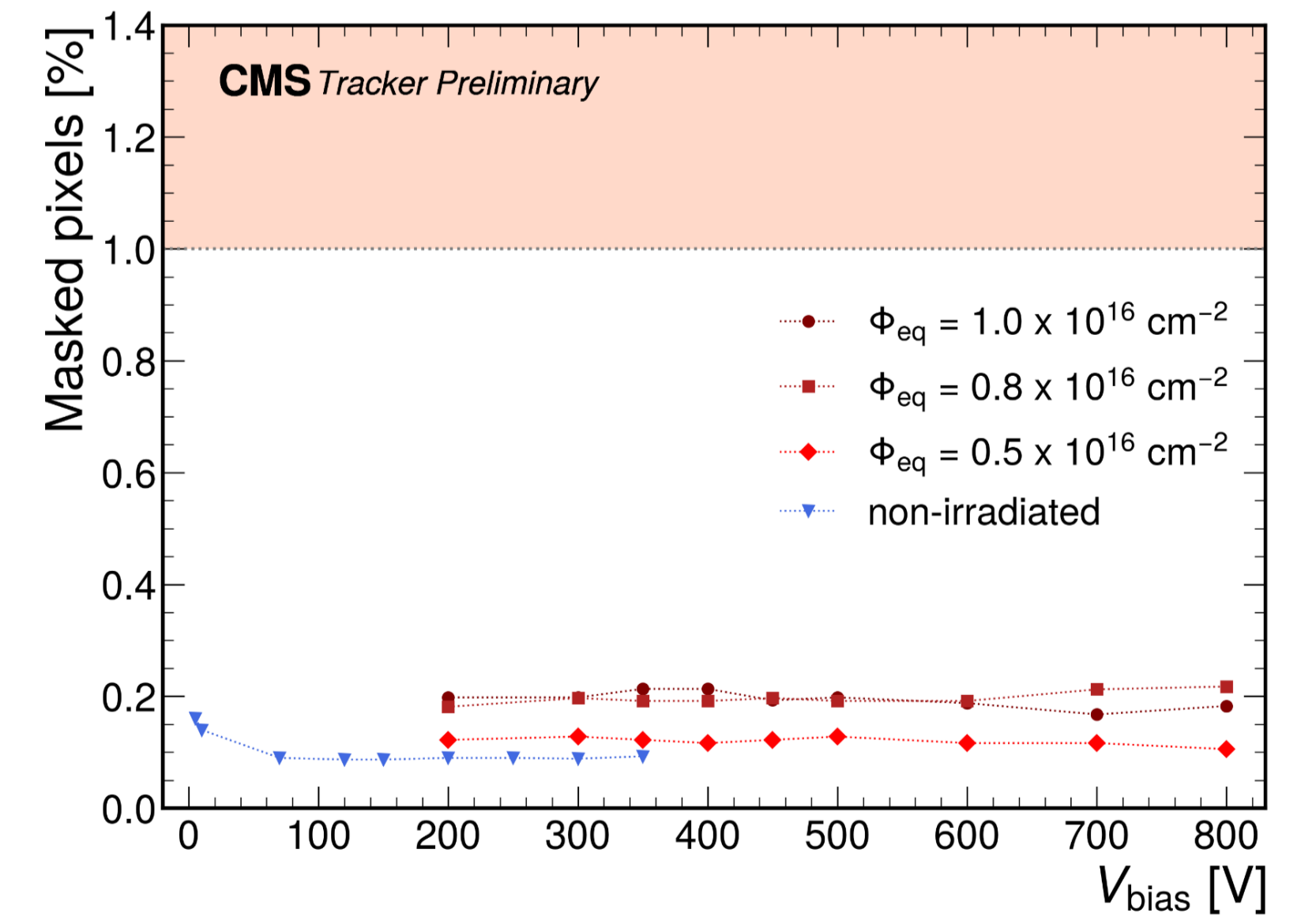
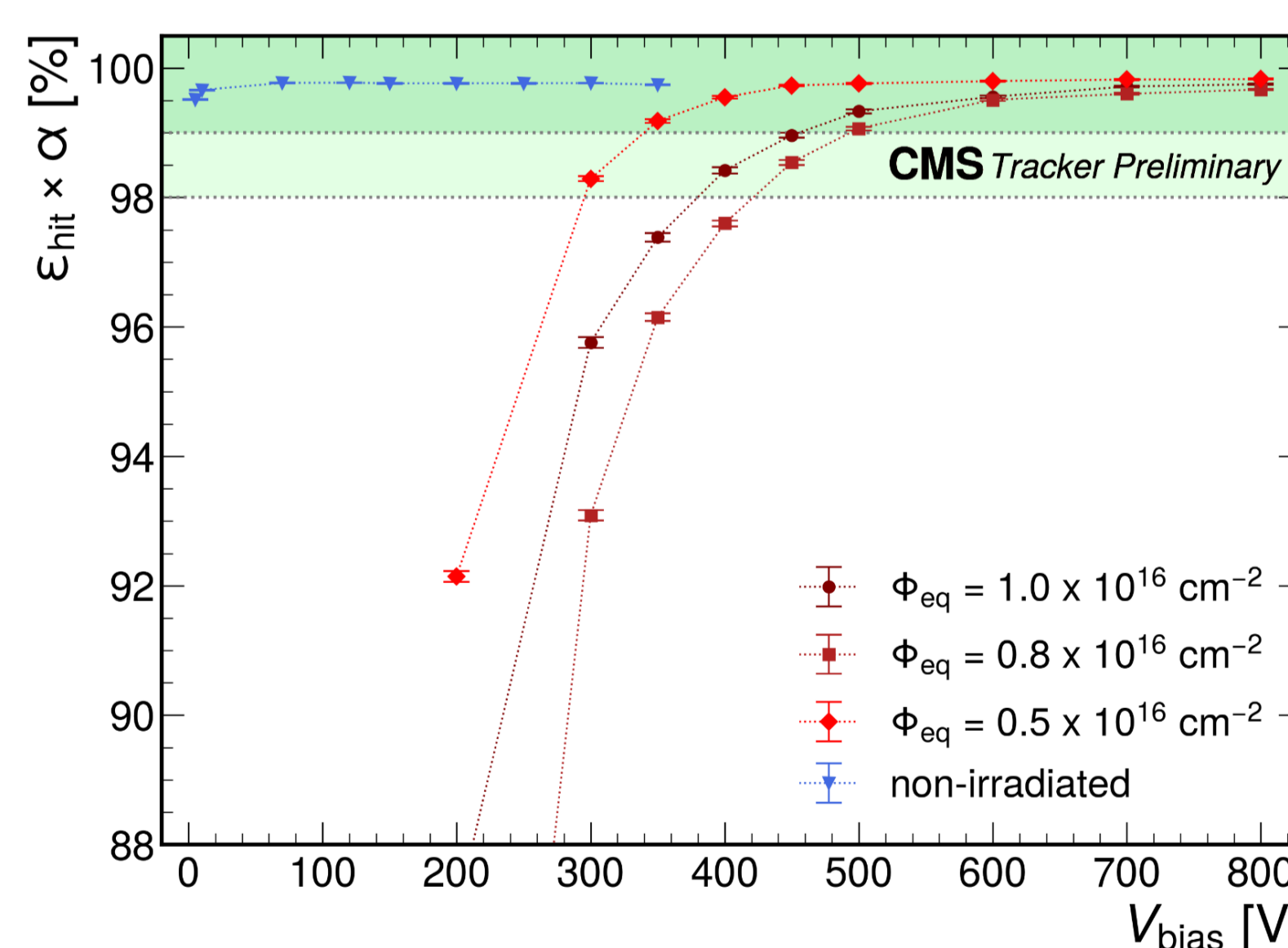
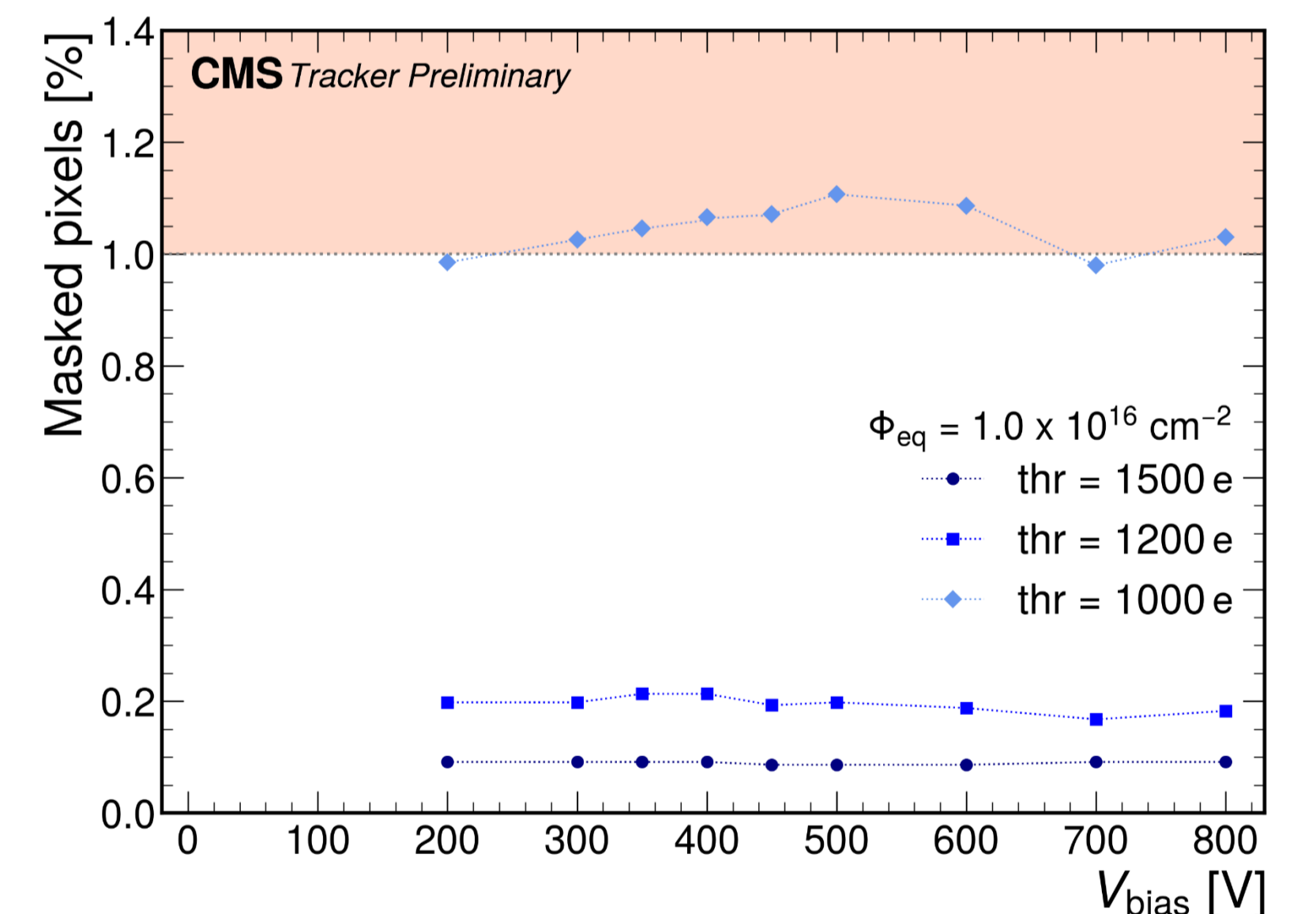
- $\sigma_{\text{hit}}^{r-\phi} < 7.2 \mu\text{m}$ in r- ϕ (25 μm pixel pitch)
- $\sigma_{\text{hit}}^z < 28.9 \mu\text{m}$ in z (100 μm pixel pitch) direction

Planar sensors equipped with RD53B_CMS chips meet all requirements

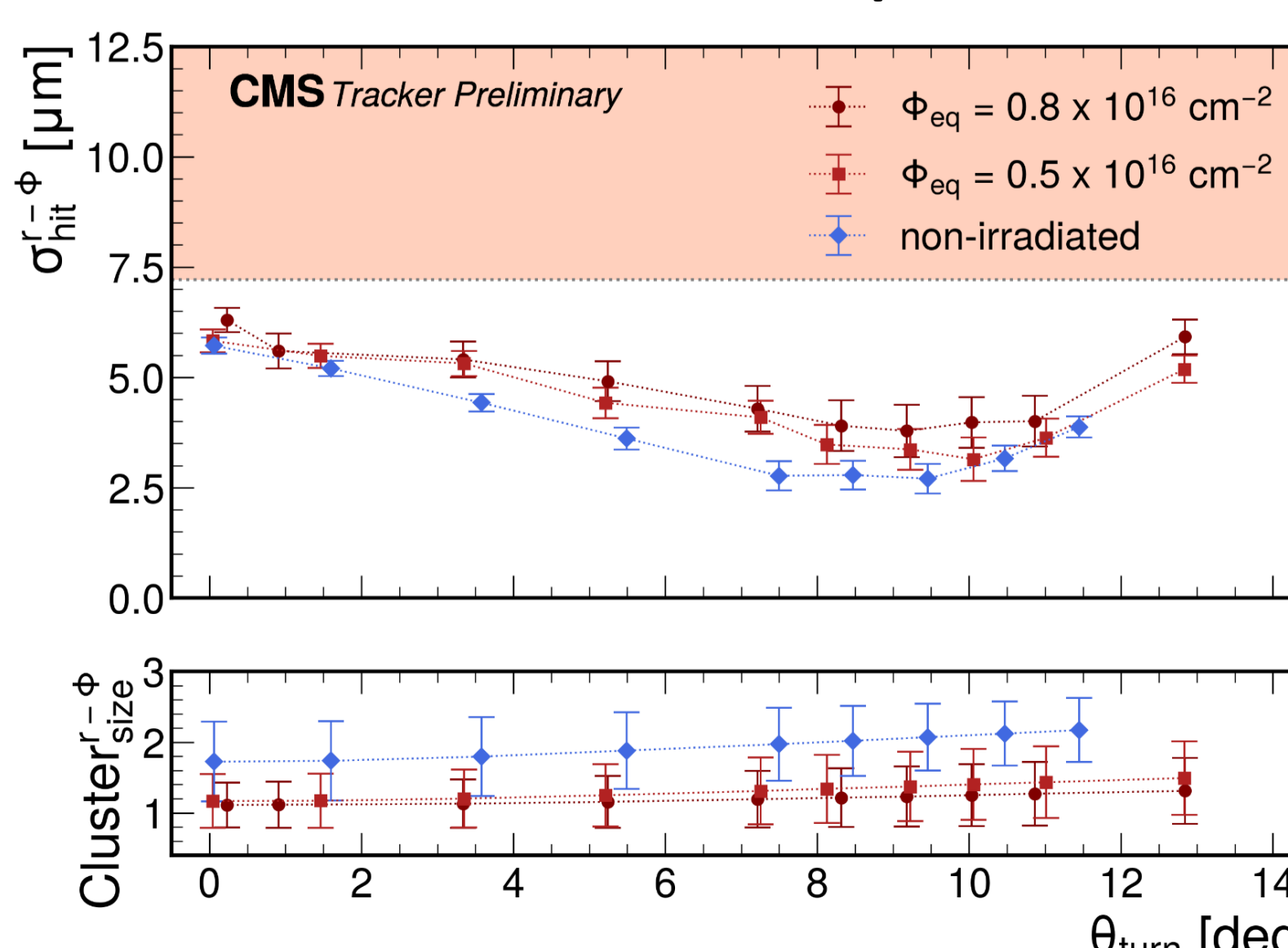
$\epsilon_{\text{hit}} \times \alpha$



Masked pixels



Resolution 25 μm



Resolution 100 μm

